



TA Technology (Shanghai) Co., Ltd.

Test Lab Attestation Letter

Date of Test: From August 31, 2012 to September 4, 2012.

Applicant Name: Quantun Electronics, LLC

FCC Id: XMHQP-350-DU2

Tested By: 
Du ruwei

Title: SAR Engineer

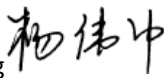
Email Address: duruwei@ta-shanghai.com

Phone No.: +86-21-50791141

Statement of Compliance: TA Technology (Shanghai) Co., Ltd. declares that this Unit has been tested in accordance with the test method identified in this test report and that we observed it being tested. It also declares that the Unit complies with the relevant limits. All instrumentation and accessories used to test this unit for compliance to the indicated test method are calibrated regularly in accordance with ISO 17025:2005 requirements by laboratories accredited by A2LA, NVLAP, or ACLAS for the measurement parameters.

The measurements were made at: TA Technology (Shanghai) Co., Ltd.
No.145, Jintang Rd, Tangzhen Industry Park, Pudong Shanghai, China

Test Lab Witness-

Approved By: 
Yang weizhong

Title of Witness: Manager

Email Address: yangweizhong@ta-shanghai.com

Phone No.: +86-21-50791141